

Novel Methods for Reducing UHP Gas Usage in Fabs

Customized Project; Sponsored by Intel

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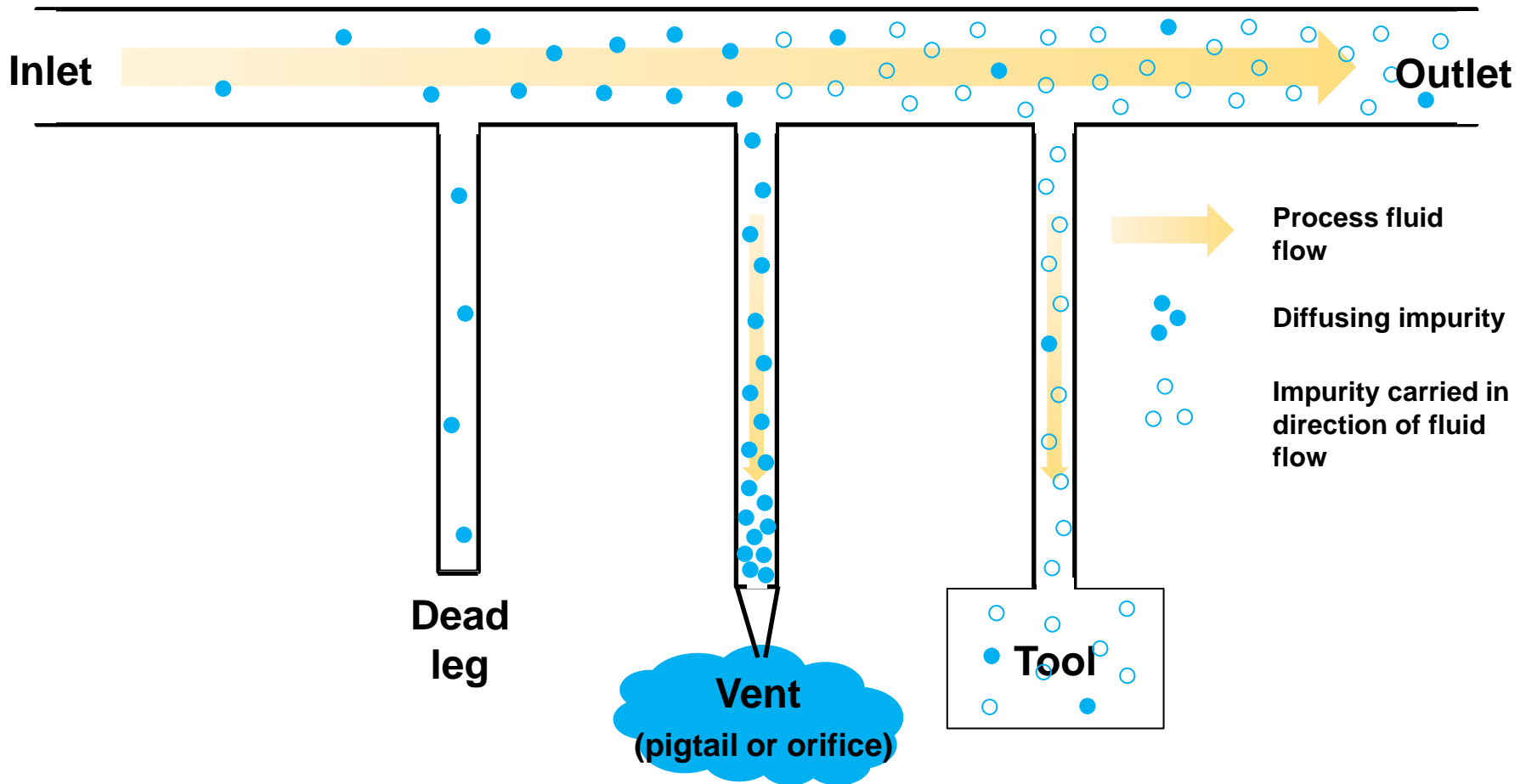
Objectives

- **Develop techniques for reducing contamination and lowering UHP gas usage in fabs:**
 - **Subtask 1: Analysis of “*back diffusion*” as a major source of contamination**
 - **Subtask 2: Novel purge methods to remove contaminants during steady operation, start-ups, or recovery from system upsets.**

Motivation and ESH Impact

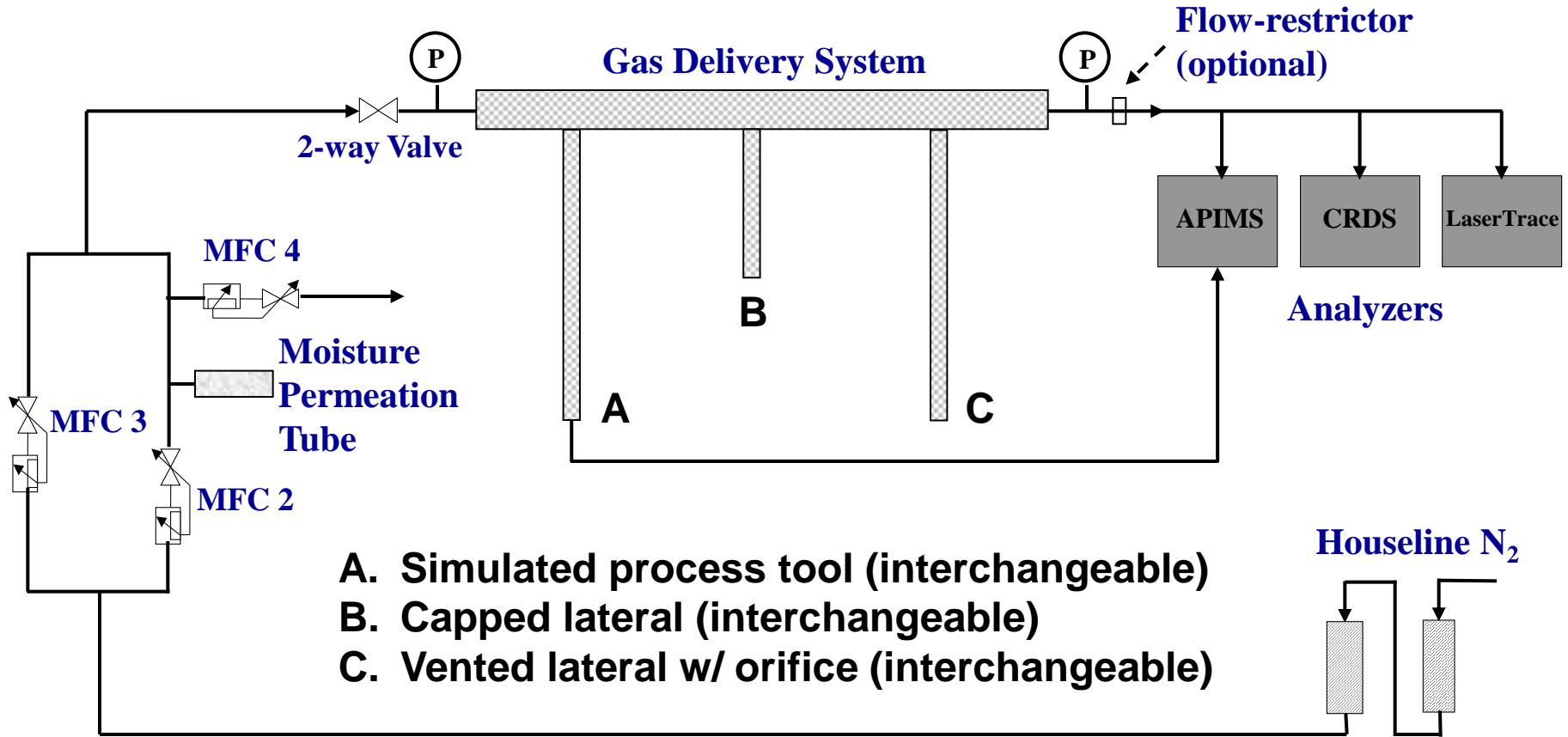
- **Contamination of gas distribution systems during operation or at start-up results in major wasting of materials, energy, and valuable tool operation time.**

Subtask 1: Back Diffusion



Experimental Testbed

Laterals Added to the Main Line



Gas distribution systems with different sizes and geometries were fabricated and provided by Intel

CRDS: high ppt – low ppm

APIMS: low ppt – low ppb

Multistage Gas Purifier System

Back Diffusion Process Simulator

Convective Flux

$$J_c = -U_3 C_g$$

Gas Phase Dispersive Flux

$$J = -D \frac{dC_g}{dz}$$

Surface Diffusive Flux

$$J_s = -D_s \frac{dC_s}{dz} - D_s \frac{k_a}{k_d} \frac{dC_g}{dz}$$

Total Dispersive Mass Flow Rate

$$\pi r^2 J_e = \pi r^2 J + 2\pi r J_s$$

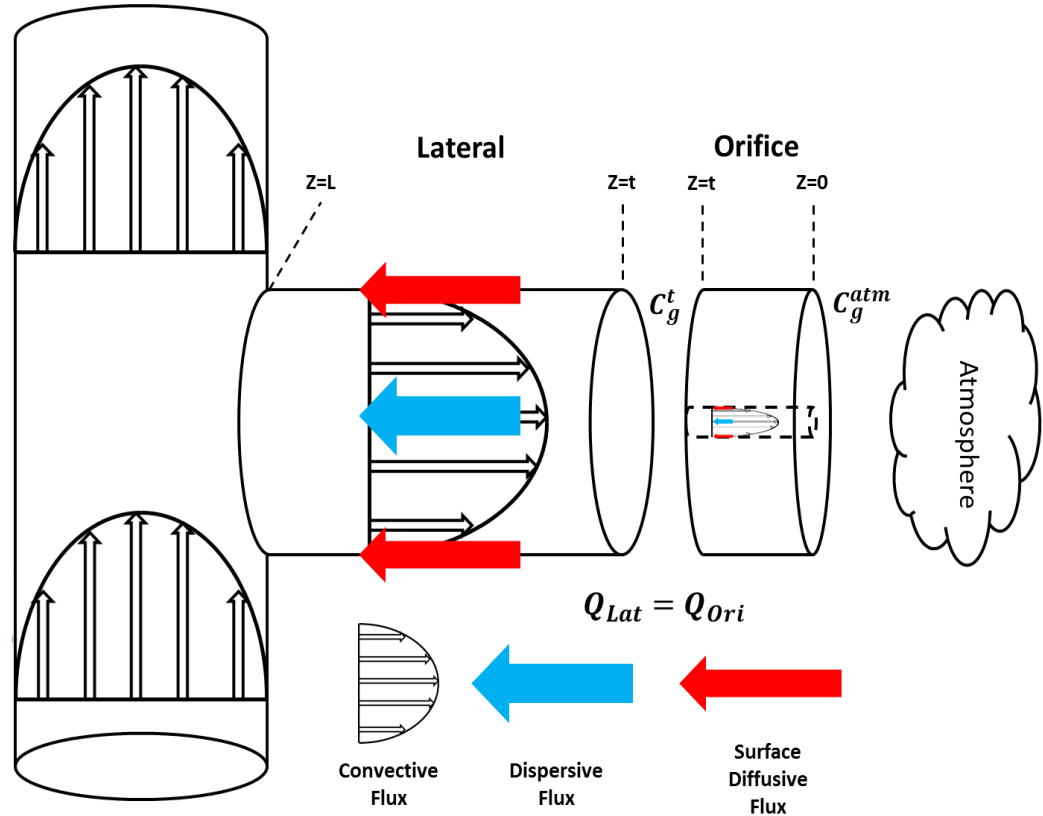
Effective Dispersion Coefficient

$$D_e = D + \frac{2}{r} D_s K_e$$

Governing Equation

$$U_3 \frac{dC_g}{dz} + D_e \frac{d^2 C_g}{dz^2} = 0$$

Convection
Effective Dispersion



Boundary Condition 1

$$z = 0, \quad D_m \left(\frac{C_g^{atm} - C_g}{t} \right) = \frac{Q_3}{A_{ori}} C_g$$

Convective Flux

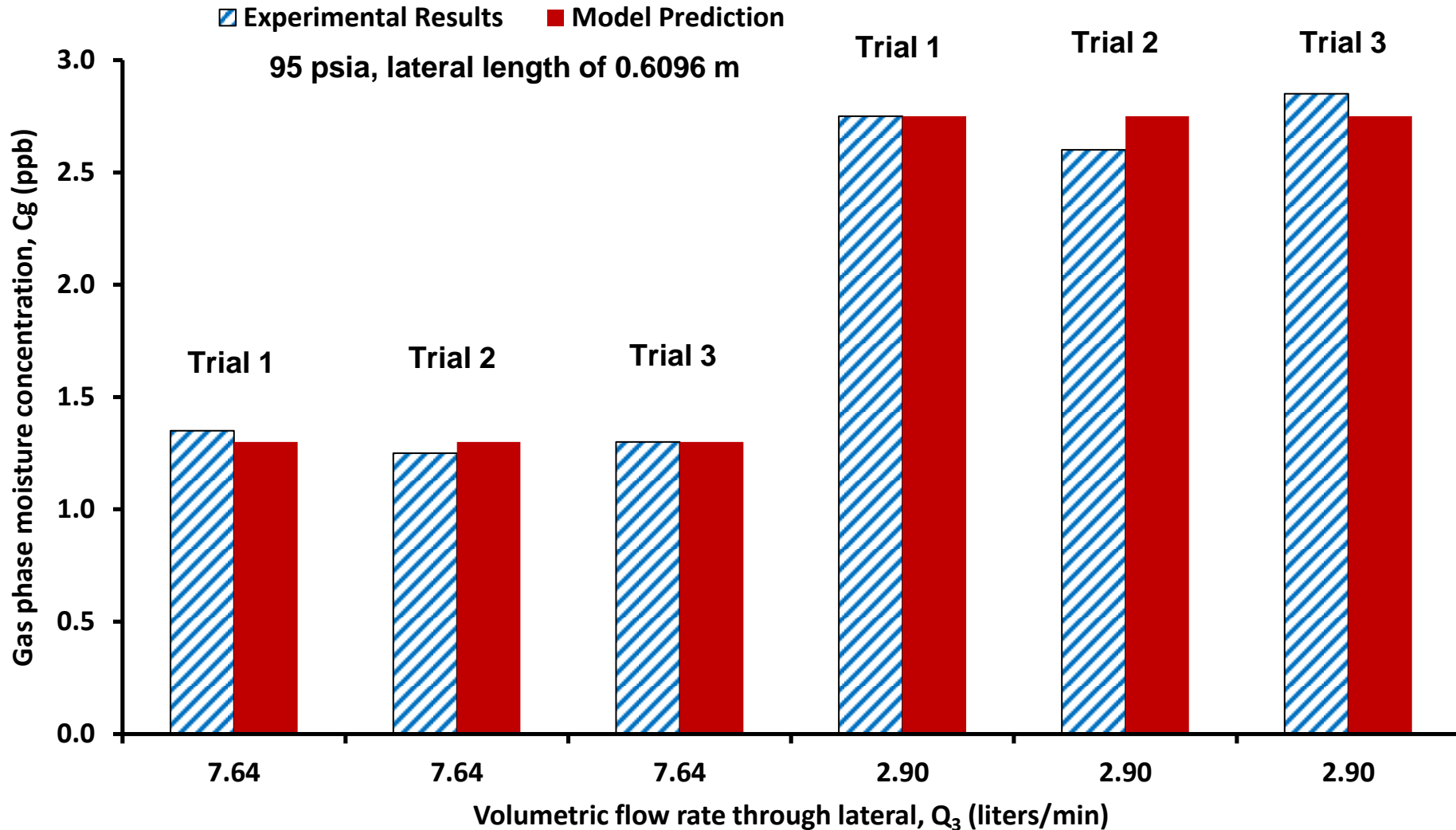
Boundary Condition 2

$$z = L, \quad C_g|_{z=L} = \left(-U_3 C_g|_{z=L} - D_e \frac{dC_g}{dz} \Big|_{z=L} \right) \frac{A_{lateral}}{Q_2}$$

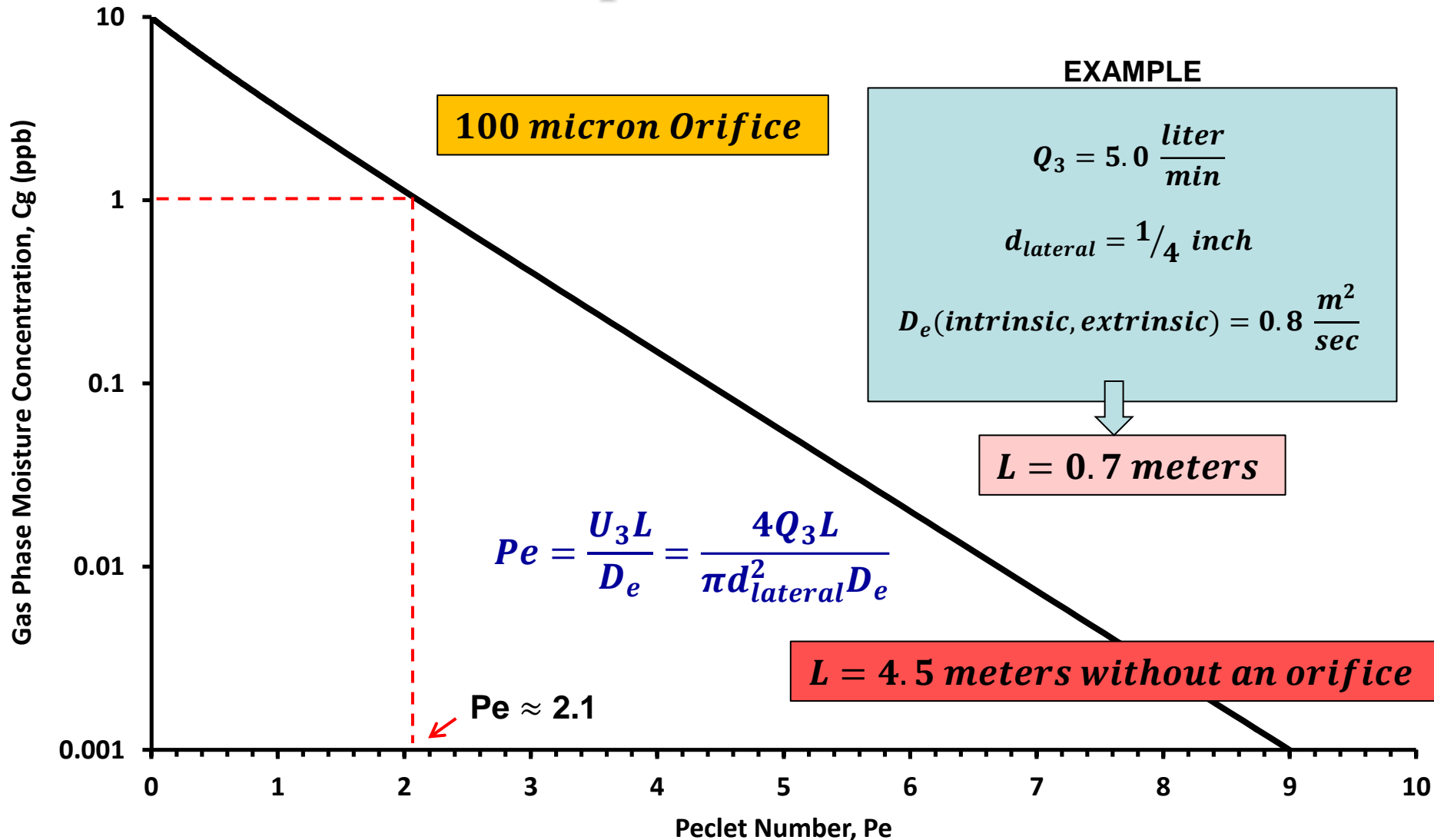
Effective Dispersive Flux

Process Simulator Verification

Simulator Prediction

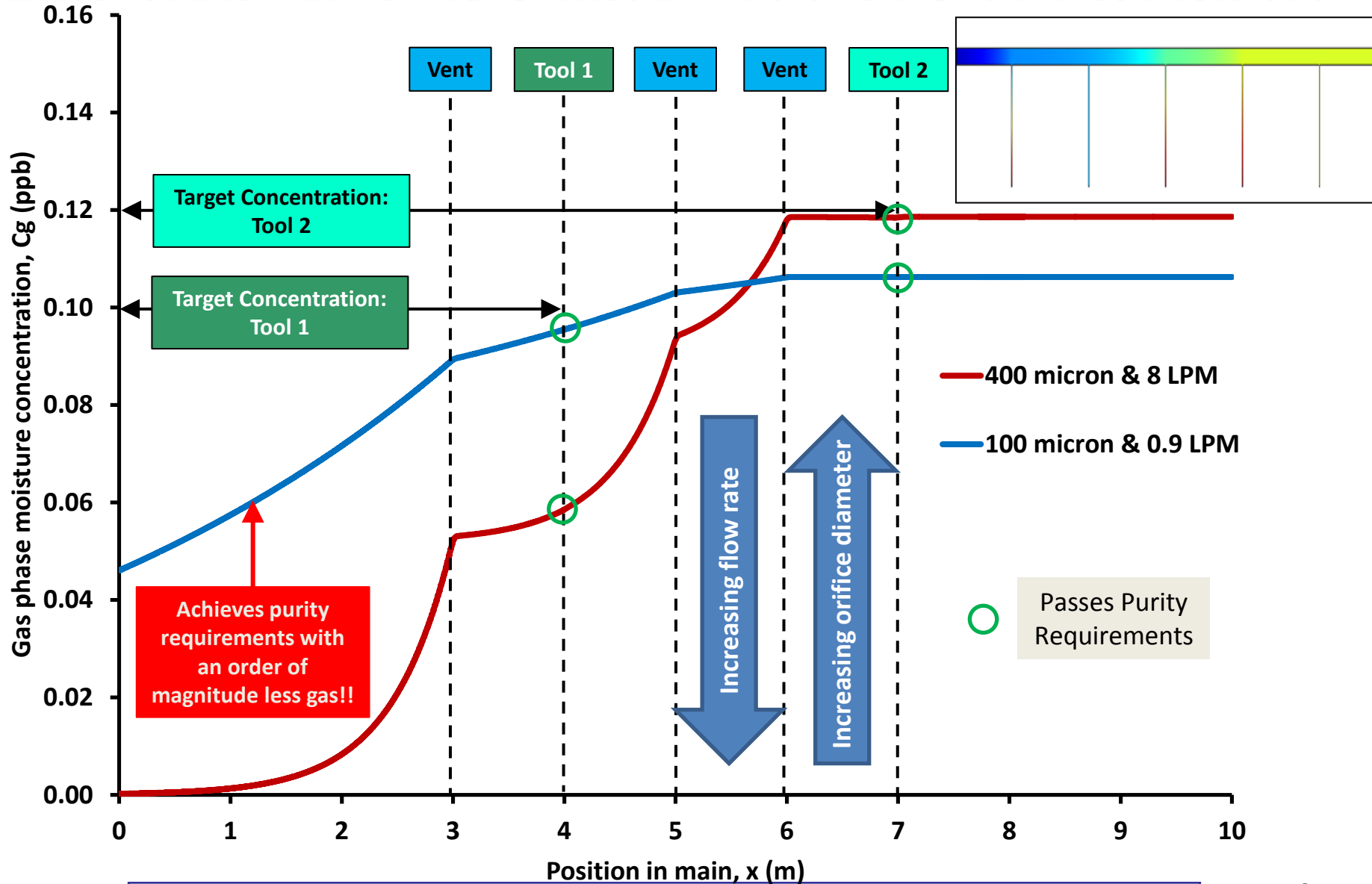


Example: Application for Design and Selection of Operational Parameters

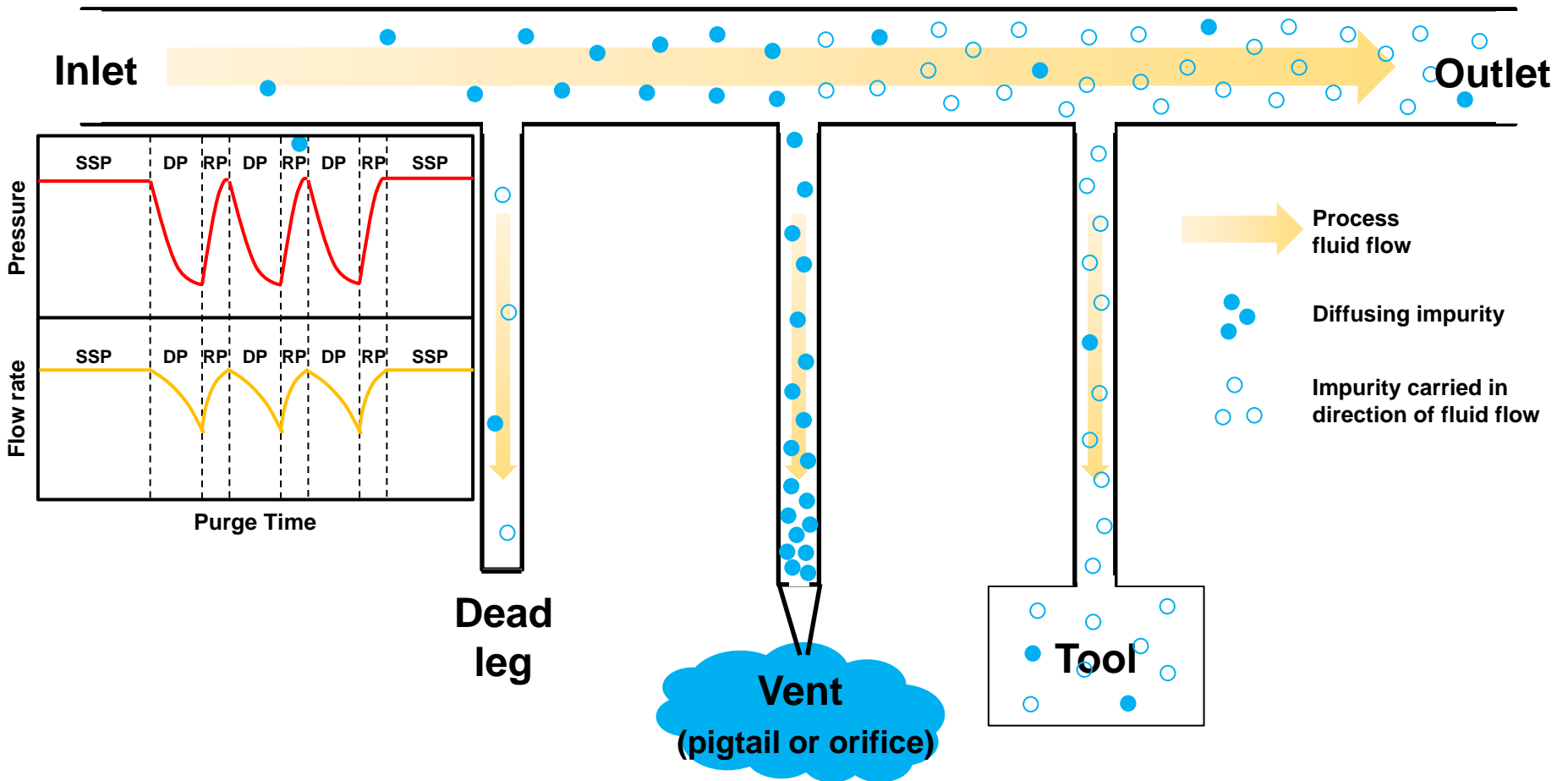


Parametric Studies

Effect of Flow Rate and Orifice Diameter on Gas Phase Moisture



Subtask 2: Novel ESH-Friendly Purge Methods



Comprehensive Purge Simulator

Continuity equation:

$$\frac{\partial P}{\partial t} = -P \frac{\partial u}{\partial x} - u \frac{\partial P}{\partial x}$$

Navier–Stokes equation:

$$\frac{\partial u}{\partial t} = -\frac{RT}{PM} \frac{\partial P}{\partial x} - u \frac{\partial u}{\partial x}$$

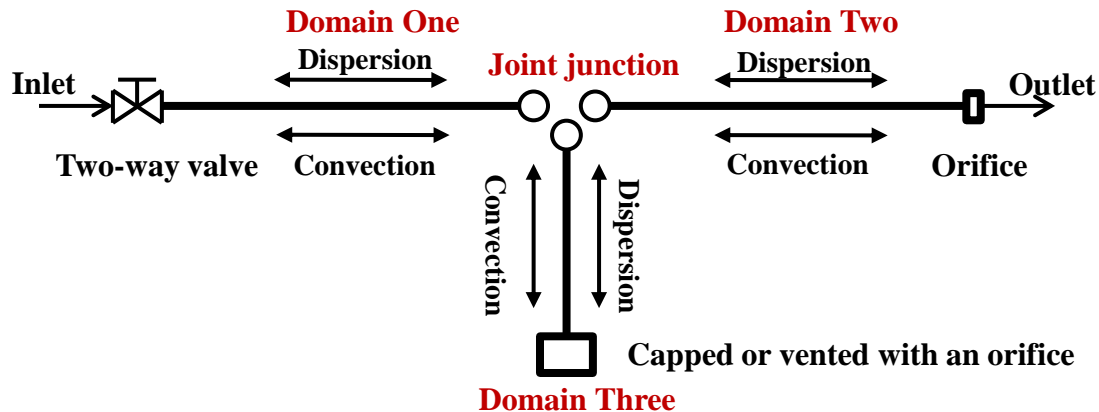
Moisture concentration in the gas phase:

$$\frac{\partial C_g}{\partial t} = \frac{1}{\partial x} (D_L \frac{\partial C_g}{\partial x}) - \frac{1}{\partial x} (u C_g) + \frac{4}{d} [(k_d C_S - k_a C_g (S_0 - C_S))]$$

Diffusion Convection Adsorption and desorption

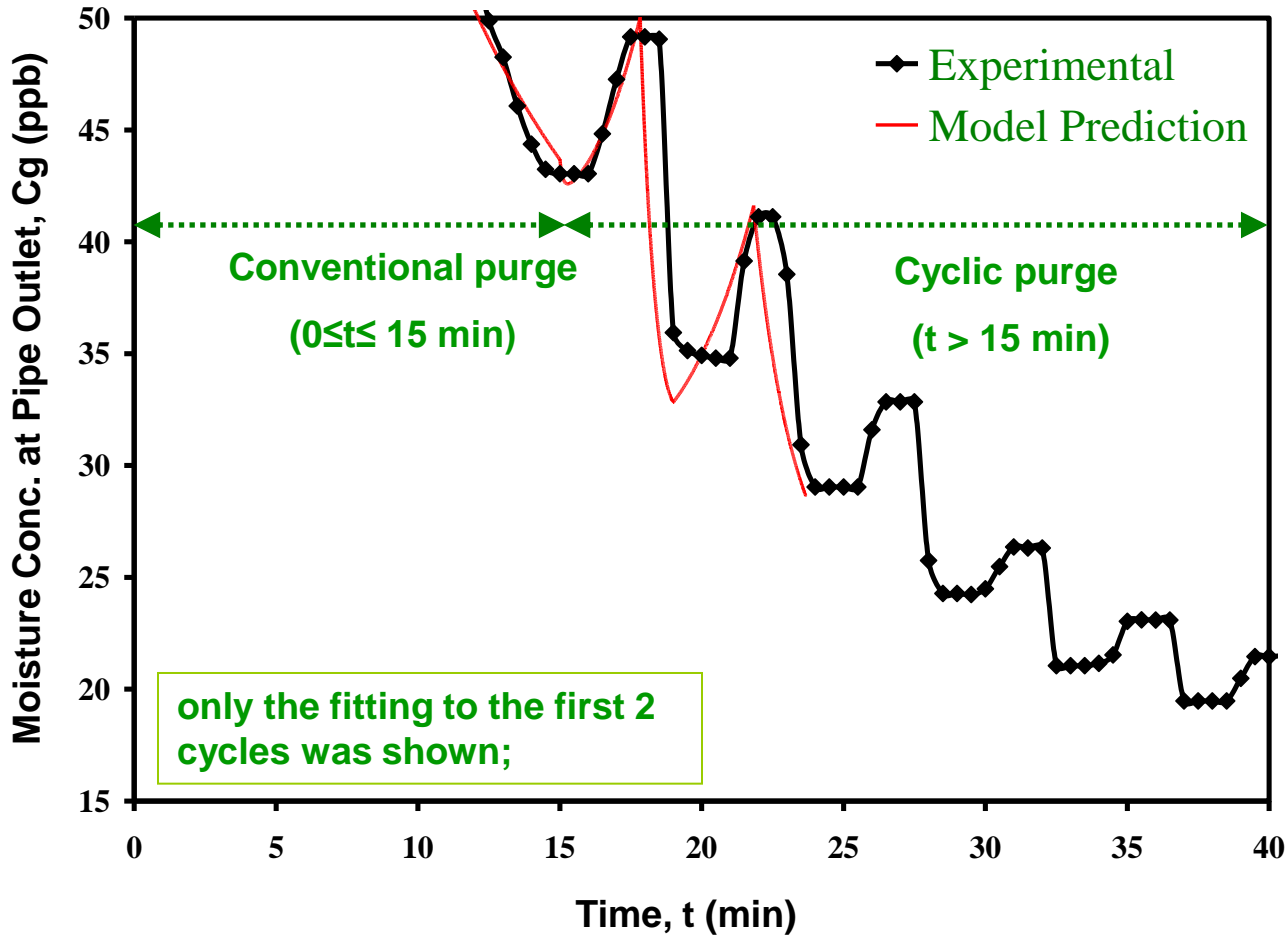
Moisture concentration on the pipe surface:

$$\frac{\partial C_s}{\partial t} = k_a C_g (S_0 - C_S) - k_d C_S$$



Simulator Verification

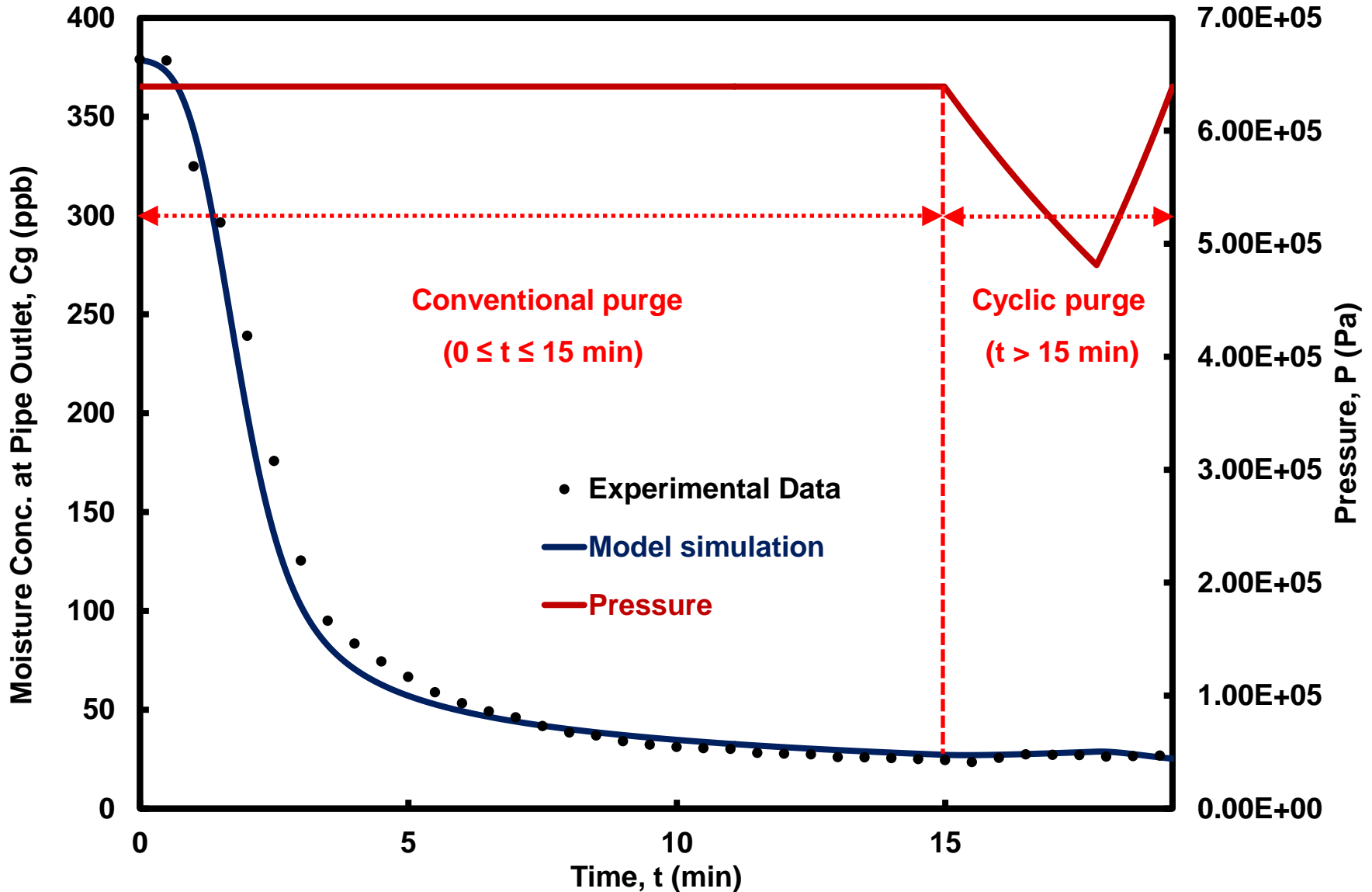
EPSS pipe with 1.5 inch OD and 76 inch length. Initial moisture conc. : 350 ppb



The process simulator well predicts combination of conventional and cyclic purge processes

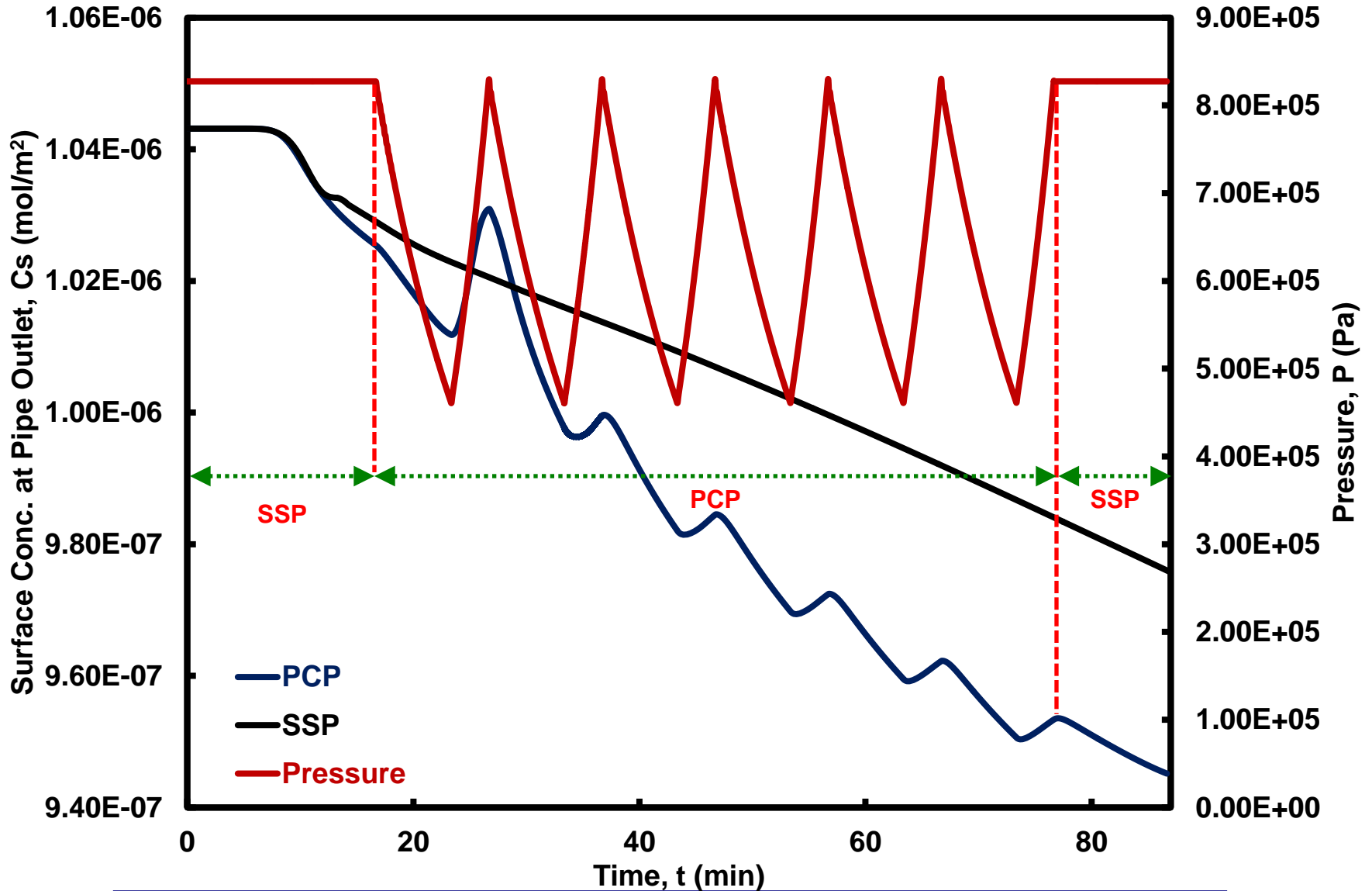
Simulator Verification

Main header: 1.5" OD, 76" length. Lateral: 0.5" OD, 30" length. Initial conc.: 380 ppb



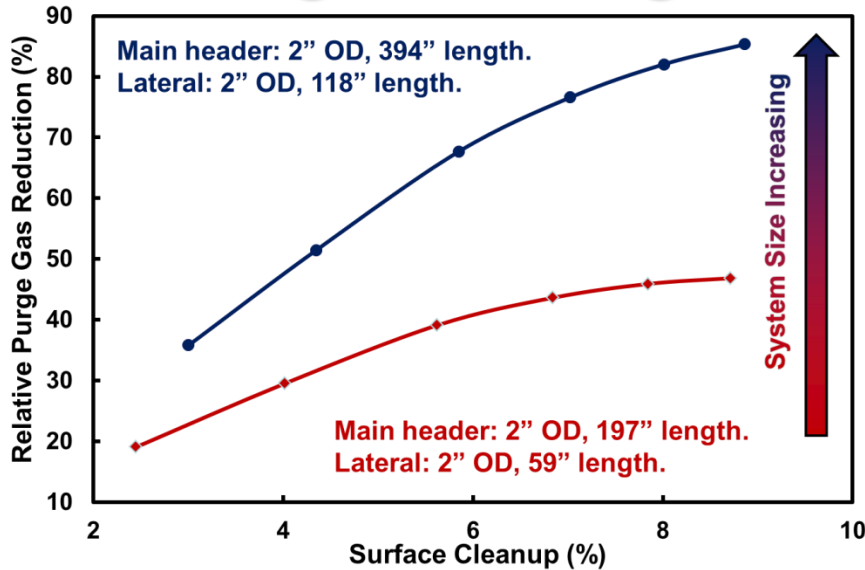
Comparison of SSP and PCP

Main header: 2" OD, 394" length. Lateral: 2" OD, 118" length. Initial conc.: 200 ppb

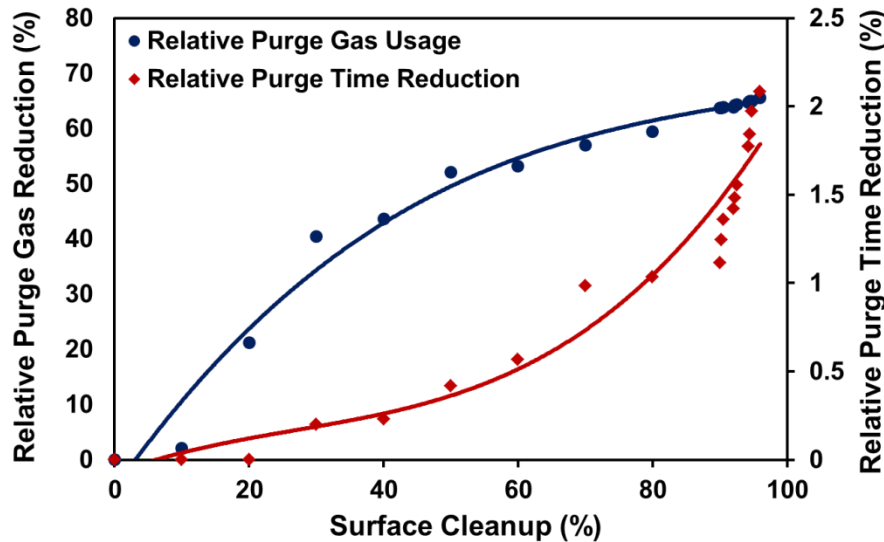


ESH/Cost Impact:

Gas Usage and Purge Time Reduction by PCP Process



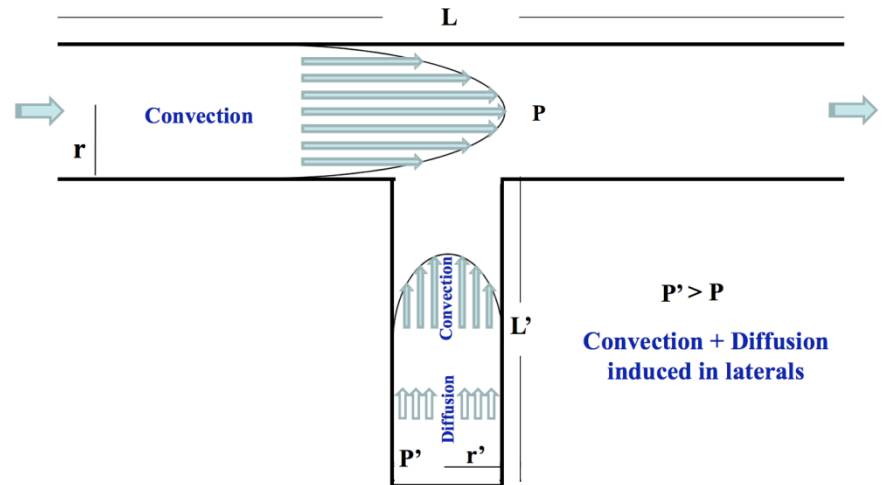
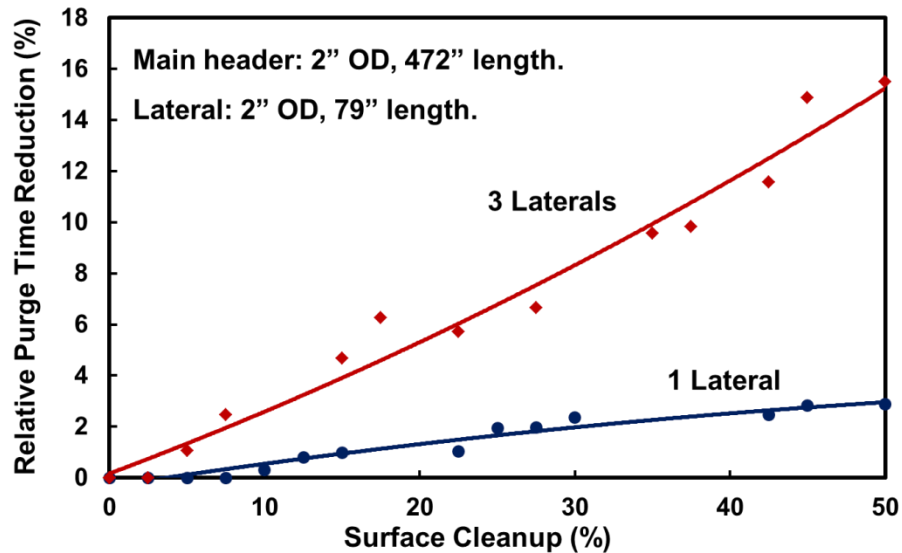
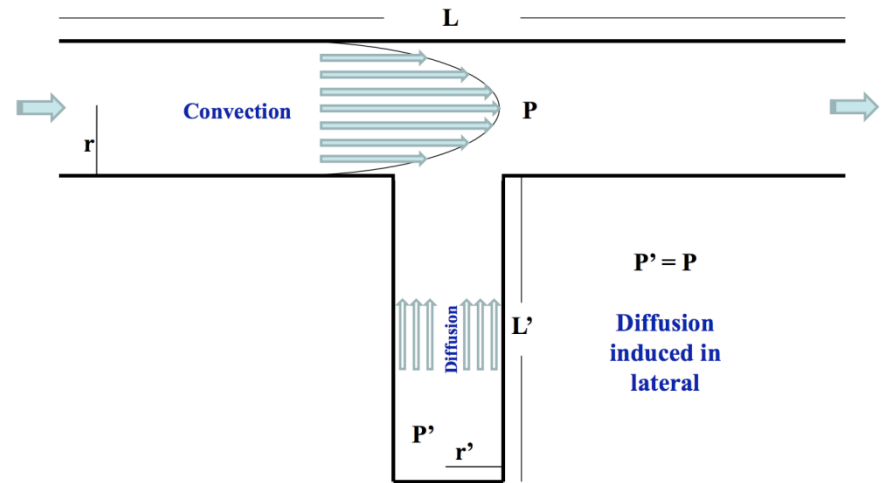
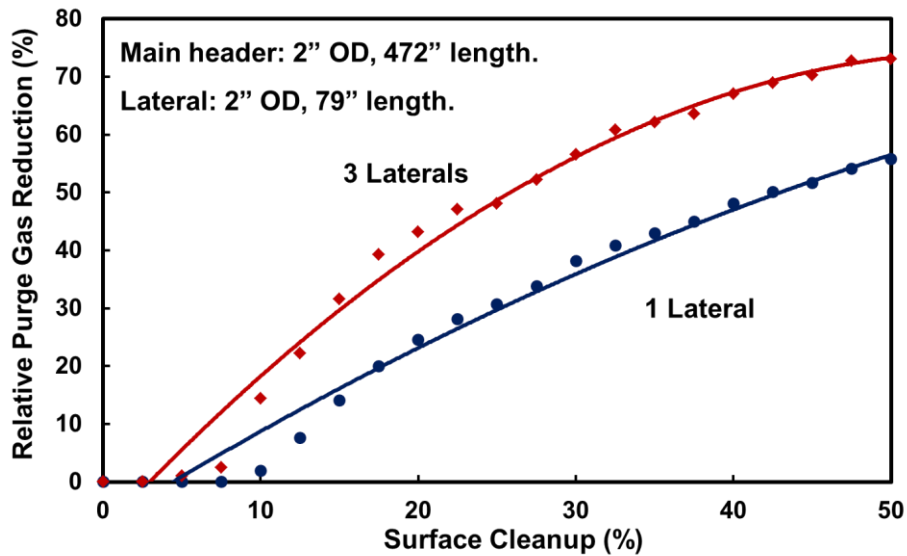
- ### System Size Effect
- The relative purge gas reduction increases with the surface cleanup.
 - PCP advantage is greater for larger systems.



Industrial Scale Purge Study

500 ft Main Section
50 ft Branches x 5

PCP Advantage for Purging Networks



Summary and Conclusions

- **A method is developed to study contamination back diffusion in gas distribution systems; last year's focus on comparison of flow restrictors options (pigtailed, valves, and orifices).**
- **Developed robust pressure cyclic purge (PCP) methods for complex systems with multiple branches.**
- **PCP reduces the down time and gas usage for purging gas distribution systems. The advantage is greater for larger networks with branches and stagnant volumes.**
- **Successful PCP requires proper (non-trivial) selection of operational parameters. Process simulation is needed to accomplish this task.**
- **Two versions of the process simulator are developed: comprehensive version for detailed research and simplified version for fab on-site usage.**

Industrial Interactions and Future Plans

- Continue joint work with Intel; some technology transfer and implementation of results at Intel fabs have already taken place.
- Prepare a user-friendly version of the process simulator available to industry
- Extend the present study to other fluids, contaminants, and components

Acknowledgements

- Carl Geisert and Gopal Rao (Intel)
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Publications and Presentations

- **Hao Wang, Farhang Shadman, Effect of Particle Size on the Adsorption and Desorption Properties of Oxide Nanoparticles, AIChE, September, 2012.**
- **Hao Wang, Farhang Shadman, Effect of Particle Size on the ESH Properties of Nano-Materials, Presentation, SRC TECHCON, September 2012.**
- **Hao Wang, Roy Dittler, Farhang Shadman, Application of Pressure-Cycle Purge in Dry-down of Ultra-High-Purity Gas Distribution Systems, Presentation, ASM American Inc., August 2012.**
- **Hao Wang, Farhang Shadman, Effect of Particle Size on the Adsorption and Desorption Properties of Oxide Nanoparticles, SRC ERC Teleconference, April, 2012.**
- **Roy Dittler, Hao Wang, Jivaan Jhothiraman, Carl Geisert, Farhang Shadman, Reducing Ultra-High-Purity (UHP) Gas Consumption By Characterization of Trace Contaminate Kinetic and Transport Behavior in UHP Fab Environments, SRC ERC Teleconference, November, 2012.**
- **Roy Dittler, Carl Geisert, Bulk Gas Distribution Dry Down Research, Intel Corp., August 2012.**